

[MEMORY MODULE TESTING/REPAIRING METHOD AND DEVICE]

Abstract of Disclosure

A memory module testing/repairing method and device that uses standby memory cells inside a memory chip to replace any faulty memory addresses found inside the memory module. The method includes testing the memory module, registering any faulty memory addresses, and finally blocking the fixed address paths to the faulty memory addresses and replacing the faulty memory addresses with standby addresses by selectively blowing an electrical fuse.

Figures